MILITARY SPECIFICATION

SEMICONDUCTOR DEVICE, TRANSISTOR, PNP, GERMANIUM
TYPES 2N1557A through 2N1560A

This amendment forms a part of Military Specification MIL-S-19500/330A (3L)
cated 15 November 1969 and is approved for use by all departments and
Agencies of the Department of Defense.

Page 2

Paragraph 1.4, VBE(sat) and VCE(sat), columns; change "VCE = 1 Vdc" to read
"I_B = -1 Adc".

Page 3

Add the following Paragraph: 4.1.1 Preconditioned-unit constituency of inspection
lots. - All semiconductor devices covered herein, each inspection lot presented for
Quality Conformance Inspection, shall have been subjected to the following preconditioning:

(a) Maintained at T_A=+100°C minimum, for 96 ± 8 hours minimum.

Page 13

Subgroup 5 of Group B, under conditions, add: "See figure 4".

Page 18

Group C, Subgroup 5, End-Point tests: Change "Same as for Subgroup 2 above", to read "Same as for Subgroup 4 above".

Add: Figure 4.

Page 20

Figure 2, bias resistor; change "9.9 " to "0-50 "

Custodian:
Army-EL

Preparing Activity:
Army-EL
Project No. 5961 - A581
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**FIGURE 4. SAFE AREA TEST CIRCUIT**

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